

Search Notes**Application/Control No.**

10/594,282

**Applicant(s)/Patent under
Reexamination**

ISHII ET AL.

Examiner

Sin J. Lee

Art Unit

1795

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EIC structure searches were reviewed again.	12/20/2009	SJL